# 2SA1124

# Silicon PNP epitaxial planar type

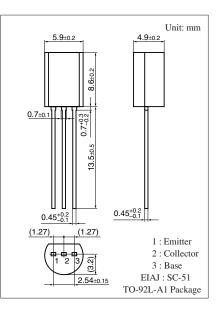
For low-frequency high breakdown voltage amplification Complementary to 2SC2632

### Features

- $\bullet$  Satisfactory forward current transfer ratio  $h_{FE}$  collector current  $I_C$  characteristics.
- $\bullet$  High collector-emitter voltage (Base open)  $V_{\mbox{CEO}}$
- $\bullet$  Small collector output capacitance (Common base, input open circuited)  $C_{ob}$
- Makes up a complementary pair with 2SC2632, which is optimum for the pre-driver stage of a 40 W to 60 W output amplifier.

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Parameter	Symbol	Rating	Unit			
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	-150	V			
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-150	V			
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	-5	V			
Collector current	I <sub>C</sub>	-50	mA			
Peak collector current	I <sub>CP</sub>	-100	mA			
Collector power dissipation	P <sub>C</sub>	1	W			
Junction temperature	Tj	150	°C			
Storage temperature	T <sub>stg</sub>	-55 to +150	°C			

#### Absolute Maximum Ratings $T_a = 25^{\circ}C$

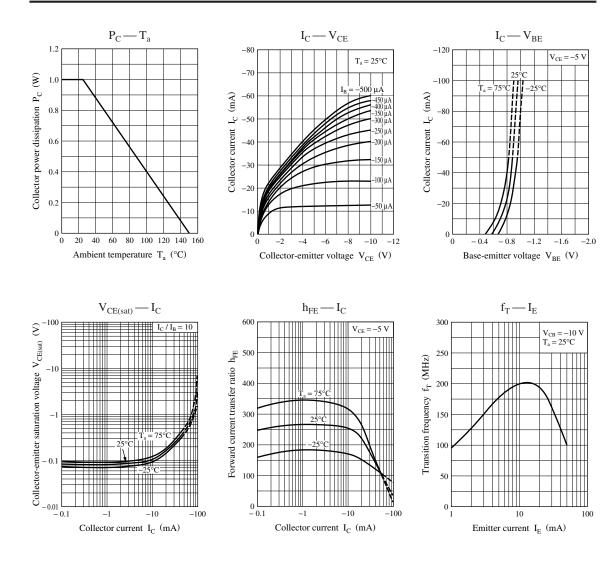


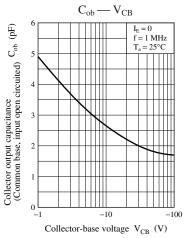
# Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_{\rm C} = -0.1 \text{ mA}, I_{\rm B} = 0$	-150			V
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	$I_{\rm E} = -10 \ \mu A, \ I_{\rm C} = 0$	-5			V
Collector-base cutoff current (Emitter open)	I <sub>CBO</sub>	$V_{CB} = -100 \text{ V}, I_E = 0$			-1	μΑ
Forward current transfer ratio *	h <sub>FE</sub>	$V_{CE} = -5 \text{ V}, I_C = -2 \text{ mA}$	130		330	—
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_{\rm C} = -30$ mA, $I_{\rm B} = -3$ mA			-1	V
Transition frequency	f <sub>T</sub>	$V_{CB} = -10 \text{ V}, I_E = 10 \text{ mA}, f = 200 \text{ MHz}$		200		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$			5	pF
(Common base, input open circuited)						
Noise voltage	NV	$V_{CE} = -10 \text{ V}, I_C = -1 \text{ mA}, G_V = 80 \text{ dB}$		150	300	mV
		$R_g = 100 \text{ k}\Omega$ , Function = FLAT				

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors. 2. \*: Rank classification

Rank	R	S
$h_{FE}$	130 to 220	185 to 330





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